

DS1201A Passive Current Probe

Low-noise, high-quality measurement signal
for side channel acquisition on embedded devices

Introduction

Measuring the power consumption of embedded technology to perform side channel analysis poses specific challenges: Power lines on embedded devices are generally noisier, signals travel at a higher speed, and there is a lot of variety in form factors as compared to smartcards. To perform side channel analysis on embedded devices, such as system-on-chip (SoC) devices and field programmable gate arrays (FPGA), our Inspector Side Channel Analysis Software and DS1201A Passive Current Probe provide a solution for tackling these challenges.

